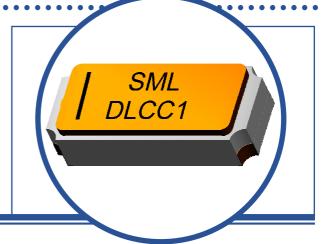
500mW ZENER DIODE



Semelab Limited

1N750AD1A

- Standard ±5% Zener Voltage Tolerance.
- Hermetic Ceramic Surface Mount Package.
- Space Level and High-Reliability Screening Options Available.



ABSOLUTE MAXIMUM RATINGS (T_A = 25°C unless otherwise stated)

V _F	Forward Voltage	$I_F = 200 \text{mA}$	1.5V
I_{ZM}	Zener Current		75mA
P_T	Total Power Dissipation at	$T_{SP} = 25^{\circ}C$	500mW
		Derate Above 25°C	TBA
Tj	Junction Temperature Range		-65 to +175°C
T _{STG}	Storage Temperature Range		-65 to +175°C
T_{SP}	Maximum Soldering Pad Temperature for 20s		300°C

THERMAL PROPERTIES

Symbols	Parameters	Max.	Units
R _{0JSP(IN)}	Thermal Resistance, Junction To Solder Pads. T _{SP} = 25°C	TBA	°C/W





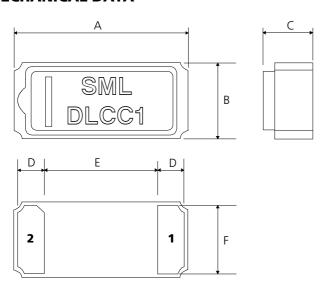
ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise stated)

Symbols	Parameters	Test Conditions	Min.	Тур	Max.	Units
V _Z (1)	Zener Voltage	I _Z = 20mA	4.465	4.7	4.935	V
Z _Z (2)	Dynamic Impedance	I _Z = 20mA			19	Ω
I _R	Reverse Current	V _R = 1.0V			2	μΑ
		$V_R = 1.0V$ $T_A = 150$ °C			30	
αV_Z	Temp Coefficient Of VZ			-0.015		%/°C

Notes

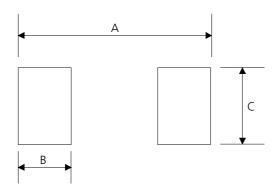
- (1) Pulse Condition: $20\text{ms} \le \text{tp} \le 50\text{ms}$, $\delta \le 2\%$
- (2) Zener impedance is derived by superimposing on I_Z a 60Hz rms ac current equal to 10% of I_Z .

MECHANICAL DATA



DLCC1 Variant A (D1A)

PAD 1	ANODE	
PAD 2	CATHODE	
DIMENSION	mm	Inches
А	4.60 ±0.20	0.181 ±0.007
В	2.00 ±0.20	0.079 ±0.007
C	1.30 ±0.20	0.051 ±0.007
D	0.70 ±0.20	0.028 ±0.007
E	3.00 ±0.20	0.118 ±0.007
F	1.80 ±0.20	0.071 ±0.007



SOLDER PAD LAYOUT

mm	Inches
5.08	0.2
1.40	0.059
2.03	0.08
	5.08 1.40

Website: http://www.semelab-tt.com

Soldering temperature should be 260°C for a maximum of 10 seconds.

500mW ZENER DIODE 1N750AD1A



SCREENING OPTIONS

Space Level (JQRS/ESA) and High Reliability options are available in accordance with the <u>High Reliability and Screening Options Handbook</u> available for download from the from the TT electronics Semelab web site.

ESA Quality Level Products are based on the testing procedures specified in the generic ESCC 5000 and in the corresponding part detail specifications.

Semelabs QR216 and QR217 processing specifications (JQRS), in conjunction with the companies ISO 9001:2000 approval present a viable alternative to the American MIL-PRF-19500 space level processing.

QR217 (Space Level Quality Conformance) is based on the quality conformance inspection requirements of MIL-PRF-19500 groups A (table V), B (table VIa), C (table VII) and also ESA / ESCC 5000 (chart F4) lot validation tests.

QR216 (Space Level Screening) is based on the screening requirements of MIL-PRF-19500 (table IV) and also ESA /ESCC 5000 (chart F3).

JQRS parts are processed to the device data sheet and screened to QR216 with conformance testing to Q217 groups A and B in accordance with MIL-STD-750 methods and procedures.

Additional conformance options are available, for example Pre-Cap Visual Inspection, Buy-Off Visit or Data Packs. These are chargeable and must be specified at the order stage (See Ordering Information). Minimum order quantities may apply.

Alternative or additional customer specific conformance or screening requirements would be considered. Contact Semelab sales with enquires.

MARKING DETAILS

Parts can be laser marked with approximately 7 characters on two lines and always includes cathode identification. Typical marking would include part or specification number, week of seal or serial number subject to available space and legibility.

Customer specific marking requirements can be arranged at the time of order.

Example Marking:



ORDERING INFORMATION

Part numbers are built up from Type, Package Variant, and screening level. The part numbers are extended to include the additional options as shown below.

Type – See Electrical Stability Characteristics Table Package Variant – See Mechanical Data Screening Level – See Screening Options (ESA / JQRS)

Additional Options:

Customer Pre-Cap Visual Inspection	.CVP
Customer Buy-Off visit	.CVB
Data Pack	.DA
Solderability Samples	.SS
Scanning Electron Microscopy	.SEM
Radiography (X-ray)	.XRAY
Total Dose Radiation Test	.RAD
MIL-PRF-19500 (QR217)	
Group B charge	.GRPB
Group B destructive mechanical samples	.GBDM (12 pieces)
Group C charge	.GRPC
Group C destructive electrical samples	.GCDE (12 pieces)
Group C destructive mechanical samples	.GCDM (6 pieces)
ESA/ESCC	
Lot Validation Testing (subgroup 1) charge	.LVT1
LVT1 destructive samples (environmental)	.L1DE (15 pieces)
LVT1 destructive samples (mechanical)	.L1DM (15 pieces)
Lot Validation Testing (subgroup 2) charge	.LVT2
LVT2 endurance samples (electrical)	.L2D (15 pieces)
Lot Validation Testing (subgroup 3) charge	.LVT3
LVT3 destructive samples (mechanical)	.L3D (5 pieces)

Additional Option Notes:

- All 'Additional Options' are chargeable and must be specified at order stage.
- 2) When Group B,C or LVT is required, additional electrical and mechanical destructive samples must be ordered
- All destructive samples are marked the same as other production parts unless otherwise requested.

Example ordering information:

The following example is for the 1N750A part with package variant A, JQRS screening, additional Group C conformance testing and a Data pack.

Part Numbers:

1N750AD1A-JQRS (Include quantity for flight parts)
1N750AD1A-JQRS.GRPC (chargeable conformance option)
1N750AD1A-JQRS.GCDE (charge for destructive parts)
1N750AD1A-JQRS.GCDM (charge for destructive parts)
1N750AD1A-JQRS.DA (charge for Data pack)

Customers with any specific requirements (e.g. marking or screening) may be supplied with a similar alternative part number (there is maximum 20 character limit to part numbers). Contact Semelab sales with enquiries

Website: http://www.semelab-tt.com

High Reliability and Screening Options Handbook link: http://www.semelab.co.uk/pdf/misc/documents/hirel_and_screening_options.pdf